IN THE CLAIMS:



7. A probe pin array, comprising:

a housing having a first and a second surface;

a plurality of non-spring loaded probe pins extending between said housing first surface and said housing second surface, wherein said plurality of non-spring loaded probe pins extend substantially perpendicularly from said housing second surface; and

at least one alignment guide extending from said housing second surface having at least one chamfered surface oriented toward said plurality of non-spring loaded probe pins.



14. A probe pin array, comprising:

a housing having a first and a second surface;

a carrier having a first surface and a second surface, wherein said carrier second surface abuts said housing first surface;

a plurality of non-spring loaded probe pins extending between said housing first surface and said housing second surface and extending between said housing first surface and said housing second surface, wherein said plurality of non-spring loaded probe pins extend substantially perpendicularly from said housing second surface; and

at least one alignment guide extending from said housing second surface having at least one chamfered surface oriented toward said plurality of non-spring loaded probe pins.